

## AO4268

# 60V N-Channel AlphaSGT™

## **General Description**

• Trench Power AlphaSGT<sup>TM</sup> technology

• Low R<sub>DS(ON)</sub>

• Low Gate Charge

## **Product Summary**

 $\begin{array}{ll} V_{DS} & 60V \\ I_D \; (at \; V_{GS} \! = \! 10V) & 19A \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 10V) & < 4.8 m\Omega \end{array}$ 

 $R_{DS(ON)}$  (at  $V_{GS}$ =4.5V) < 6.5m $\Omega$ 

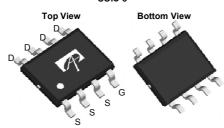
## **Applications**

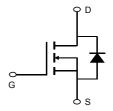
• Synchronous Rectification for AC-DC Quick Charger

100% UIS Tested 100% Rg Tested



#### SOIC-8





Orderable Part Number Package Type		Form	Minimum Order Quantity
AO4268	SO-8	Tape & Reel	3000

Absolute Maximum Ratings	T <sub>A</sub> =25°C unless of	therwise noted
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Absolute Maximum Ratings 1,4-23 C unless otherwise noted						
Parameter		Symbol	Maximum	Units		
Drain-Source Voltage		V <sub>DS</sub>	60	V		
Gate-Source Voltage	)	$V_{GS}$	±20	V		
Continuous Drain	T <sub>A</sub> =25°C		19			
Current	T <sub>A</sub> =70°C	ID	14.5	A		
Pulsed Drain Current C		I <sub>DM</sub>	76			
Avalanche Current C		I <sub>AS</sub>	30	A		
Avalanche energy	L=0.3mH <sup>C</sup>	E <sub>AS</sub>	135	mJ		
V <sub>DS</sub> Spike	10µs	V <sub>SPIKE</sub>	72	V		
	T <sub>A</sub> =25°C	В	3.1	W		
Power Dissipation <sup>B</sup>	T <sub>A</sub> =70°C	$-P_{D}$	2	T **		
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C		

Thermal Characteristics						
Parameter		Symbol	Тур	Max	Units	
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{\theta JA}$	31	40	°C/W	
Maximum Junction-to-Ambient AD	Steady-State	IX <sub>θ</sub> JA	59	75	°C/W	
Maximum Junction-to-Lead	Steady-State	$R_{\theta JL}$	16	24	°C/W	



### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	ID=250µA, V <sub>GS</sub> =0V		60			V
	Zero Gate Voltage Drain Current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V				1	μΑ
I <sub>DSS</sub>			T <sub>J</sub> =55°C			5	
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$		1.3	1.8	2.3	V
		V <sub>GS</sub> =10V, I <sub>D</sub> =19A			4	4.8	mΩ
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance		T <sub>J</sub> =125°C		6.3	7.6	
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =16A			5.2	6.5	mΩ
<b>9</b> FS	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =19A			83		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V			0.7	1	V
Is	Maximum Body-Diode Continuous Cur	is Current				4	Α
DYNAMIC	PARAMETERS						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V, f=1MHz			2500		pF
C <sub>oss</sub>	Output Capacitance				670		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			65		pF	
$R_g$	Gate resistance	f=1MHz		0.5	1.2	2	Ω
SWITCHI	NG PARAMETERS	•	·		•	•	•
Q <sub>g</sub> (10V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =30V, I <sub>D</sub> =19A			44	65	nC
Q <sub>g</sub> (4.5V)	Total Gate Charge				21	30	nC
$Q_{gs}$	Gate Source Charge	V <sub>GS</sub> -10V, V <sub>DS</sub> -30V, 1	ID-1374		6.5		nC
$Q_{gd}$	Gate Drain Charge				8.5		nC
t <sub>D(on)</sub>	Turn-On DelayTime				7.5		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =30V, $R_L$ =1.6 $\Omega$ , $R_{GEN}$ =3 $\Omega$			6.5		ns
t <sub>D(off)</sub>	Turn-Off DelayTime				38		ns
t <sub>f</sub>	Turn-Off Fall Time				8		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =19A, di/dt=500A/μ	s		22		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	e I <sub>F</sub> =19A, di/dt=500A/μs			80		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25° C. The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =150° C, using  $\leq$  10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}$ =150° C. Ratings are based on low frequency and duty cycles to keep

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initialT<sub>J</sub>=25° C.

D. The  $R_{0JA}$  is the sum of the thermal impedance from junction to lead  $R_{0JL}$  and lead to ambient. E. The static characteristics in Figures 1 to 6 are obtained using <300 $\mu$ s pulses, duty cycle 0.5% max. F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=150° C. The SOA curve provides a single pulse rating.



0

0

2

6

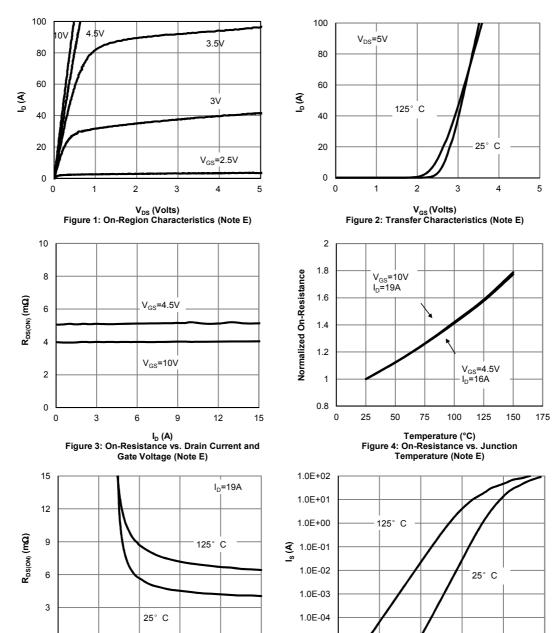
V<sub>GS</sub> (Volts)
Figure 5: On-Resistance vs. Gate-Source Voltage

(Note E)

8

10

#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



1.0E-05

0.0

0.2

0.6

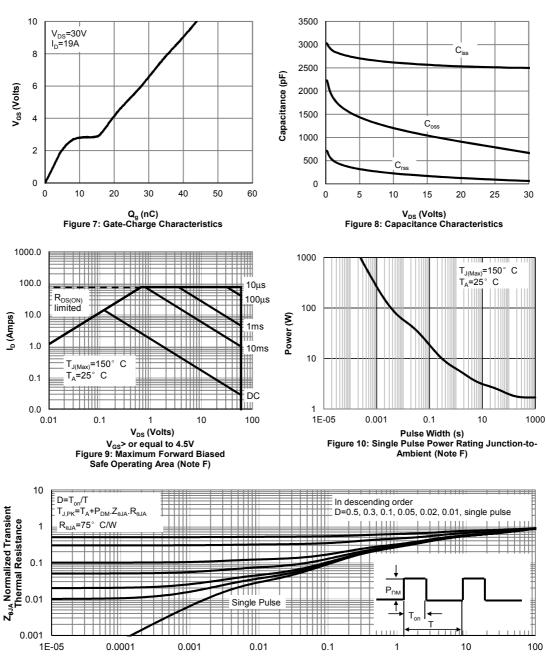
V<sub>SD</sub> (Volts) Figure 6: Body-Diode Characteristics (Note E)

8.0

1.0



#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



Figure A: Gate Charge Test Circuit & Waveforms

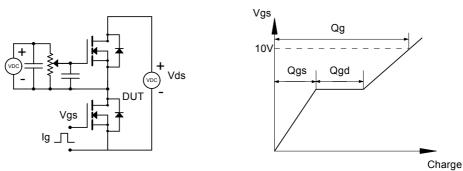


Figure B: Resistive Switching Test Circuit & Waveforms

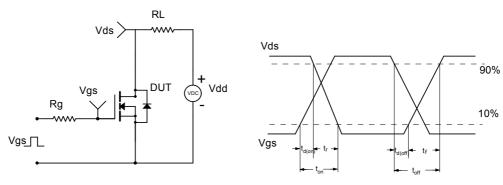


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

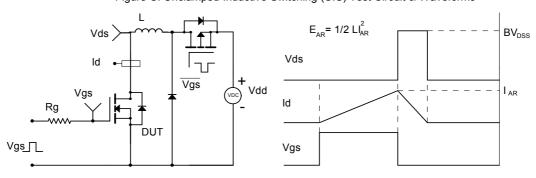


Figure D: Diode Recovery Test Circuit & Waveforms

